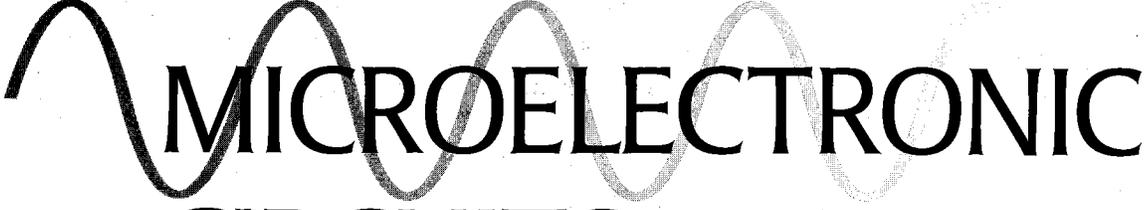


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Cover Illustration: The chip shown is the ADXL-50 surface-micromachined accelerometer. For the first time, sensor and signal conditioning are combined on a single monolithic chip. In its earliest application, it was a key factor in the improved reliability and reduced cost of modern automotive airbag systems. Photo reprinted with permission of Analog Devices, Inc.



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